

HEXFET® TRANSISTORS IRFF9110

**P-CHANNEL
 POWER MOSFETS
 TO-39 PACKAGE**



- IRFF9111**
- IRFF9112**
- IRFF9113**

-100 Volt, 1.2 Ohm HEXFET

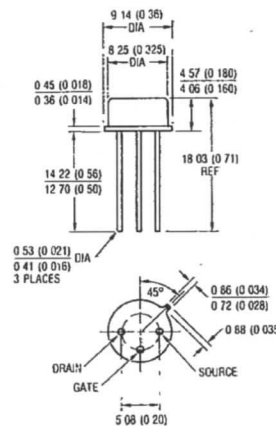
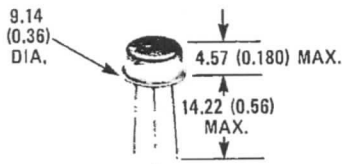
Features:

- P-Channel Versatility
- Fast Switching
- Low Drive Current
- Ease of Paralleling
- Excellent Temperature Stability

Product Summary

Part Number	V _{DS}	R _{DS(on)}	I _D
IRFF9110	-100V	1.2Ω	-2.6A
IRFF9111	-60V	1.2Ω	-2.6A
IRFF9112	-100V	1.6Ω	-2.3A
IRFF9113	-60V	1.6Ω	-2.3A

CASE STYLE AND DIMENSIONS



Conforms to JEDEC Outline TO-205AF (TO-39)
 Dimensions in Millimeters and (Inches)

NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.



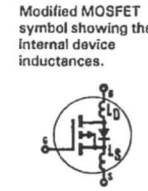
IRFF9110, IRFF9111, IRFF9112, IRFF9113 Devices

Absolute Maximum Ratings

Parameter	IRFF9110	IRFF9111	IRFF9112	IRFF9113	Units
V_{DS} Drain — Source Voltage ①	-100	-60	-100	-60	V
V_{DGR} Drain — Gate Voltage ($R_{GS} = 20\text{ k}\Omega$) ①	-100	-60	-100	-60	V
$I_D @ T_C = 25^\circ\text{C}$ Continuous Drain Current	-2.6	-2.6	-2.3	-2.3	A
I_{DM} Pulsed Drain Current ③	-10	-10	-9.0	-9.0	A
V_{GS} Gate — Source Voltage	± 20				V
$P_D @ T_C = 25^\circ\text{C}$ Max. Power Dissipation	15 (See Fig. 14)				W
Linear Derating Factor	0.12 (See Fig. 14)				W/K ④
I_{LM} Inductive Current, Clamped	(See Fig. 15 and 16) $L = 100\mu\text{H}$				A
T_J Operating Junction and T_{stg} Storage Temperature Range	-10	-10	-9.0	-9.0	$^\circ\text{C}$
Lead Temperature	300 (0.063 in. (1.6mm) from case for 10s)				$^\circ\text{C}$

Electrical Characteristics @ $T_C = 25^\circ\text{C}$ (Unless Otherwise Specified)

Parameter	Type	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS} Drain — Source Breakdown Voltage	IRFF9110 IRFF9112	-100	—	—	V	$V_{GS} = 0\text{V}$ $I_D = -250\mu\text{A}$
	IRFF9111 IRFF9113	-60	—	—	V	
$V_{GS(th)}$ Gate Threshold Voltage	ALL	-2.0	—	-4.0	V	$V_{DS} = V_{GS}$, $I_D = -250\mu\text{A}$
I_{GSS} Gate — Source Leakage Forward	ALL	—	—	-100	nA	$V_{GS} = -20\text{V}$
I_{GSS} Gate — Source Leakage Reverse	ALL	—	—	100	nA	$V_{GS} = 20\text{V}$
I_{DSS} Zero Gate Voltage Drain Current	ALL	—	—	-250	μA	$V_{DS} = \text{Max. Rating}$, $V_{GS} = 0\text{V}$
		—	—	-1000	μA	$V_{DS} = \text{Max. Rating} \times 0.8$, $V_{GS} = 0\text{V}$, $T_C = 125^\circ\text{C}$
$I_{D(on)}$ On-State Drain Current ②	IRFF9110 IRFF9111	-2.6	—	—	A	$V_{DS} > I_{D(on)} \times R_{DS(on)}$ max., $V_{GS} = -10\text{V}$
	IRFF9112 IRFF9113	-2.3	—	—	A	
$R_{DS(on)}$ Static Drain — Source On-State Resistance ②	IRFF9110 IRFF9111	—	1.0	1.2	Ω	$V_{GS} = -10\text{V}$, $I_D = -1.5\text{A}$
	IRFF9112 IRFF9113	—	1.2	1.6	Ω	
g_{fs} Forward Transconductance ②	ALL	0.8	1.1	—	S (V)	$V_{DS} > I_{D(on)} \times R_{DS(on)}$ max., $I_D = -1.5\text{A}$
C_{iss} Input Capacitance	ALL	—	180	250	pF	$V_{GS} = 0\text{V}$, $V_{DS} = -25\text{V}$, $f = 1.0\text{ MHz}$
C_{oss} Output Capacitance	ALL	—	85	100	pF	See Fig. 10
C_{rss} Reverse Transfer Capacitance	ALL	—	30	35	pF	
$t_{d(on)}$ Turn-On Delay Time	ALL	—	15	30	ns	$V_{DD} = -50\text{V}$, $I_D = -1.5\text{A}$, $Z_o = 50\Omega$
t_r Rise Time	ALL	—	30	60	ns	See Fig. 17
$t_{d(off)}$ Turn-Off Delay Time	ALL	—	20	40	ns	(MOSFET switching times are essentially independent of operating temperature.)
t_f Fall Time	ALL	—	20	40	ns	
Q_g Total Gate Charge (Gate-Source Plus Gate-Drain)	ALL	—	8.5	11	nC	$V_{GS} = -15\text{V}$, $I_D = -5.0\text{A}$, $V_{DS} = 0.8\text{V Max. Rating}$. See Fig. 18 for test circuit. (Gate charge is essentially independent of operating temperature.)
Q_{gs} Gate-Source Charge	ALL	—	3.8	—	nC	
Q_{gd} Gate-Drain ("Miller") Charge	ALL	—	4.7	—	nC	
L_D Internal Drain Inductance	ALL	—	5.0	—	nH	Measured from the drain lead, 5mm (0.2 in.) from header to center of die.
L_S Internal Source Inductance	ALL	—	15	—	nH	Measured from the source lead, 5mm (0.2 in.) from header to source bonding pad.



Thermal Resistance

R_{thJC} Junction-to-Case	ALL	—	—	8.33	K/W ④	
R_{thJA} Junction-to-Ambient	ALL	—	—	175	K/W ④	Typical socket mount

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Source-Drain Diode Ratings and Characteristics

I_S	Continuous Source Current (Body Diode)	IRFF9110	-	-	-2.6	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier.
		IRFF9111	-	-	-2.3	A	
I_{SM}	Pulse Source Current (Body Diode) ③	IRFF9110	-	-	-10	A	
		IRFF9111	-	-	-9.0	A	
V_{SD}	Diode Forward Voltage ②	IRFF9110	-	-	-5.5	V	$T_C = 25^\circ\text{C}, I_S = -2.6\text{A}, V_{GS} = 0\text{V}$
		IRFF9111	-	-	-5.3	V	$T_C = 25^\circ\text{C}, I_S = -2.3\text{A}, V_{GS} = 0\text{V}$
t_{rr}	Reverse Recovery Time	ALL	-	120	-	ns	$T_J = 150^\circ\text{C}, I_F = -2.6\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$
Q_{RR}	Reverse Recovered Charge	ALL	-	6.0	-	μC	$T_J = 150^\circ\text{C}, I_F = -2.6\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$
t_{on}	Forward Turn-on Time	ALL	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.				



- ① $T_J = 25^\circ\text{C}$ to 150°C . ② Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$. ③ Repetitive Rating: Pulse width limited by max. junction temperature. See Transient Thermal Impedance Curve (Fig. 5).
- ④ $\text{K/W} = \text{C/W}$
 $\text{W/K} = \text{W}/^\circ\text{C}$

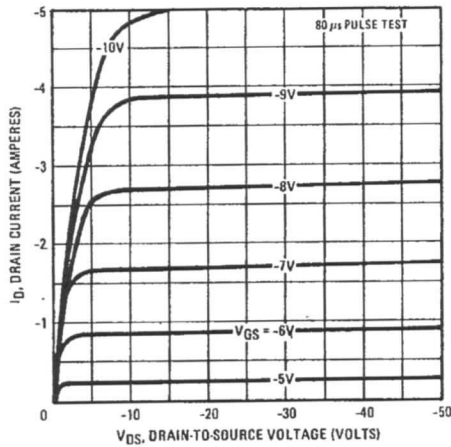


Fig. 1 - Typical Output Characteristics

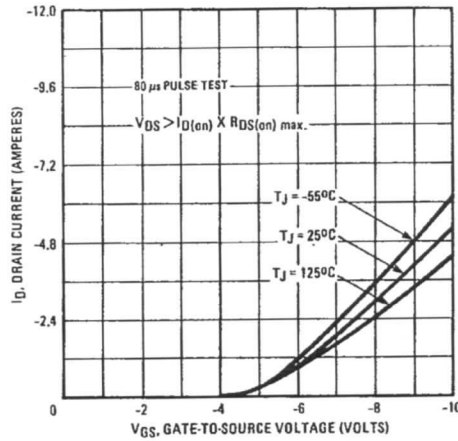


Fig. 2 - Typical Transfer Characteristics

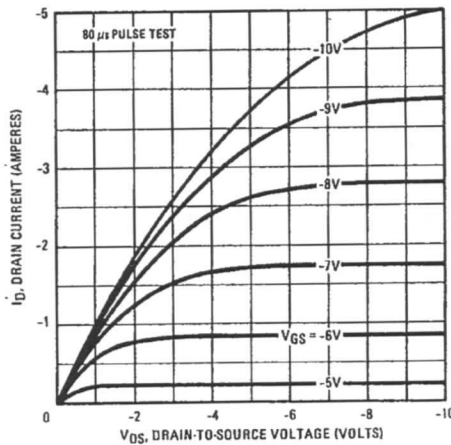


Fig. 3 - Typical Saturation Characteristics

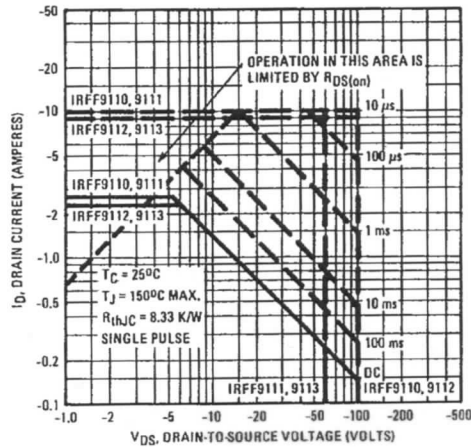


Fig. 4 - Maximum Safe Operating Area